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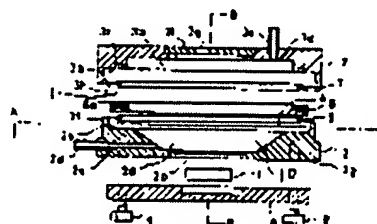
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(54) INSTRUMENT FOR VACUUM DRYING, PRESS-STICKING AND MEASURING SOLUTION SAMPLE FOR ATR SPECTROSCOPY

(57)Abstract:

PURPOSE: To improve the measurement accuracy of a soln. component by forming the 1st and 2nd hermetic chambers by a thin elastic sheet to a rigid hollow body so that the thin elastic sheet brings a thin solid film of solute into tight contact with a prism face when the inside of the 1st hermetic chamber is evacuated and the inside of the 2nd hermetic chamber is pressurized.

CONSTITUTION: The inside of the rigid hollow body is partitioned by the thin elastic sheet 4 to form the 1st and 2nd hermetic chambers 10, 11. The prism 1 is exposed to the outside and the hermetic chamber 10 and a soln. sample is coated on the surface exposed into the hermetic chamber 10. The inside of the hermetic chamber 10 is evacuated through a vent pipe 2d. The soln. sample is vacuum-dried while the contact of the sheet 4 with the soln. sample is prevented to form the thin solid film of the solute on the prism 1 face. The inside of the hermetic chamber 11 is then pressurized through an intake pipe 3e and the thin solid film of the solute is pressed by the sheet 4 so as to contact tightly with the face of the prism 1. An incident luminous flux is made incident on the prism 1 face at a specified angle in this state and the component of the solute is measured with good accuracy by an ATR spectroscopic method.



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